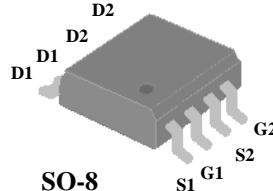


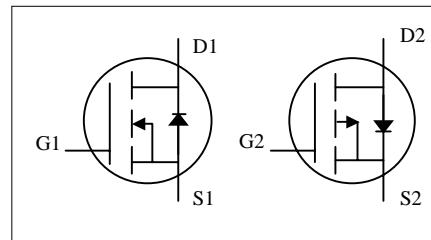
AP4513GM

**Pb Free Plating Product**
**Advanced Power  
Electronics Corp.**
*N AND P-CHANNEL ENHANCEMENT**MODE POWER MOSFET*
**▼ Simple Drive Requirement**
**▼ Low On-resistance**
**▼ Fast Switching Performance**
**▼ RoHS Compliant**

**Description**

The Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SO-8 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.

N-CH	$BV_{DSS}$	35V
	$R_{DS(ON)}$	36mΩ
	$I_D$	5.8A
P-CH	$BV_{DSS}$	-35V
	$R_{DS(ON)}$	68mΩ
	$I_D$	-4.3A


**Absolute Maximum Ratings**

Symbol	Parameter	Rating		Units
		N-channel	P-channel	
$V_{DS}$	Drain-Source Voltage	35	-35	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	$\pm 20$	V
$I_D @ T_A=25^\circ C$	Continuous Drain Current <sup>3</sup>	5.8	-4.3	A
$I_D @ T_A=70^\circ C$	Continuous Drain Current <sup>3</sup>	4.7	-3.4	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	20	-20	A
$P_D @ T_A=25^\circ C$	Total Power Dissipation	2		W
	Linear Derating Factor	0.016		W/°C
$E_{AS}$	Single Pulse Avalanche Energy <sup>4</sup>	12.5	12.5	mJ
$I_{AR}$	Avalanche Current	5	-5	A
$E_{AR}$	Repetitive Avalanche Energy <sup>1</sup>	0.05	0.05	mJ
$T_{STG}$	Storage Temperature Range	-55 to 150		°C
$T_J$	Operating Junction Temperature Range	-55 to 150		°C

**Thermal Data**

Symbol	Parameter	Value	Unit
R <sub>thj-a</sub>	Thermal Resistance Junction-ambient <sup>3</sup>	Max.	62.5 °C/W



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## N-CH Electrical Characteristics@T<sub>j</sub>=25°C(unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	35	-	-	V
Δ BV <sub>DSS</sub> /Δ T <sub>j</sub>	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA	-	0.03	-	V/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V, I <sub>D</sub> =5A	-	-	36	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =3A	-	-	60	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	1	-	3	V
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =5A	-	7	-	S
I <sub>DSS</sub>	Drain-Source Leakage Current (T <sub>j</sub> =25°C)	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V	-	-	1	uA
	Drain-Source Leakage Current (T <sub>j</sub> =70°C)	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V	-	-	25	uA
I <sub>GSS</sub>	Gate-Source Leakage	V <sub>GS</sub> =±20V	-	-	±100	nA
Q <sub>g</sub>	Total Gate Charge <sup>2</sup>	I <sub>D</sub> =5A	-	6	10	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =28V	-	2	-	nC
Q <sub>gd</sub>	Gate-Drain ("Miller") Charge	V <sub>GS</sub> =4.5V	-	3	-	nC
t <sub>d(on)</sub>	Turn-on Delay Time <sup>2</sup>	V <sub>DS</sub> =15V	-	8	-	ns
t <sub>r</sub>	Rise Time	I <sub>D</sub> =1A	-	7	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time	R <sub>G</sub> =3.3Ω, V <sub>GS</sub> =10V	-	16	-	ns
t <sub>f</sub>	Fall Time	R <sub>D</sub> =15Ω	-	3	-	ns
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V	-	470	750	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =25V	-	90	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f=1.0MHz	-	60	-	pF

## Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V <sub>SD</sub>	Forward On Voltage <sup>2</sup>	I <sub>S</sub> =1.7A, V <sub>GS</sub> =0V	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> =5A, V <sub>GS</sub> =0V	-	17	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI/dt=100A/μs	-	11	-	nC



## P-CH Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=-250\mu\text{A}$	-35	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to $25^\circ\text{C}, I_{\text{D}}=-1\text{mA}$	-	-0.03	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=-10\text{V}, I_{\text{D}}=-4\text{A}$	-	-	68	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{D}}=-2\text{A}$	-	-	100	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=-250\mu\text{A}$	-1	-	-3	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=-10\text{V}, I_{\text{D}}=-4\text{A}$	-	6	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current ( $T=25^\circ\text{C}$ )	$V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-1	$\mu\text{A}$
	Drain-Source Leakage Current ( $T=70^\circ\text{C}$ )	$V_{\text{DS}}=-24\text{V}, V_{\text{GS}}=0\text{V}$	-	-	-25	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$	-	-	$\pm 100$	nA
$Q_g$	Total Gate Charge <sup>2</sup>	$I_{\text{D}}=-4\text{A}$	-	6	10	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=-28\text{V}$	-	1	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-4.5\text{V}$	-	4	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time <sup>2</sup>	$V_{\text{DS}}=-15\text{V}$	-	8	-	ns
$t_r$	Rise Time	$I_{\text{D}}=-1\text{A}$	-	7	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega, V_{\text{GS}}=-10\text{V}$	-	20	-	ns
$t_f$	Fall Time	$R_D=15\Omega$	-	4	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	410	660	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=-25\text{V}$	-	95	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	70	-	pF

## Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_S=-1.7\text{A}, V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_S=-4\text{A}, V_{\text{GS}}=0\text{V}$	-	21	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge	$dI/dt=-100\text{A}/\mu\text{s}$	-	16	-	nC

## Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .
- 3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board , t  $\leq 10\text{sec}$  ;  $135^\circ\text{C}/\text{W}$  when mounted on min. copper pad.
- 4.Starting  $T_j=25^\circ\text{C}$  ,  $V_{\text{DD}}=25\text{V}$  ,  $L=1\text{mH}$  ,  $R_G=25\Omega$



# AP4513GM

## N-Channel

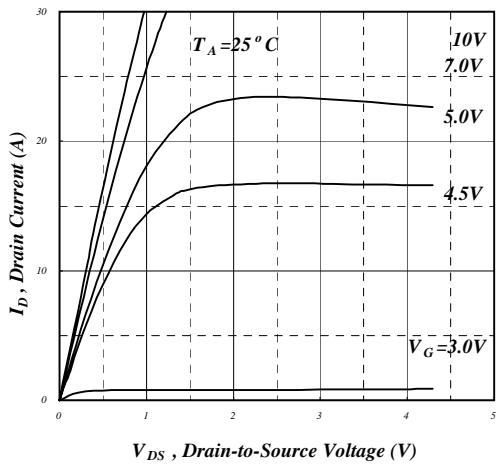


Fig 1. Typical Output Characteristics

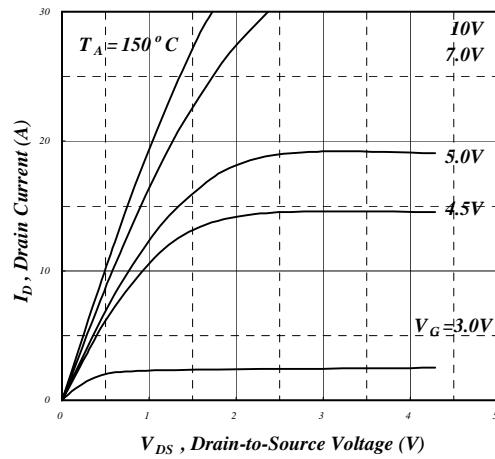


Fig 2. Typical Output Characteristics

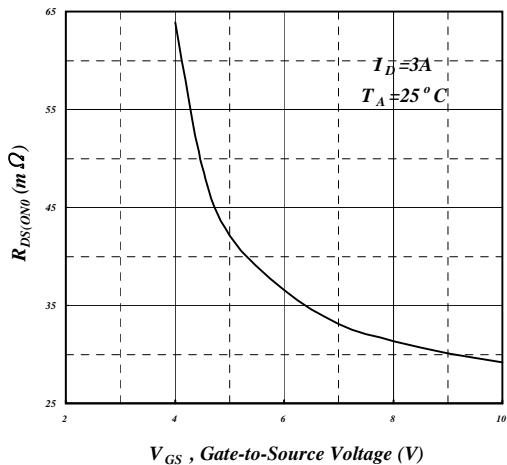


Fig 3. On-Resistance v.s. Gate Voltage

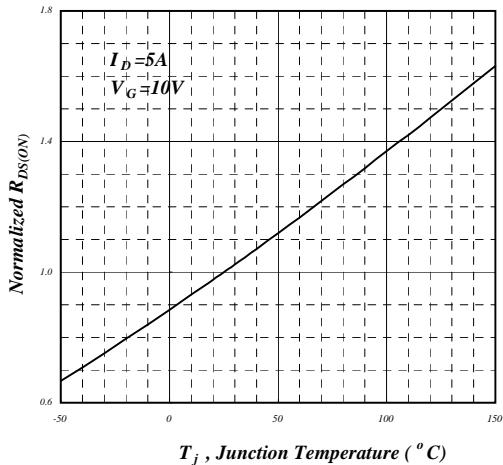


Fig 4. Normalized On-Resistance v.s. Junction Temperature

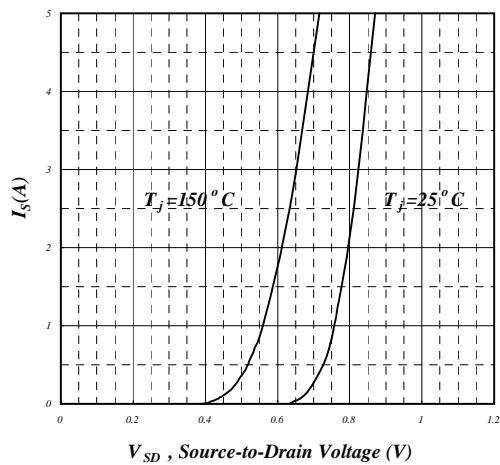


Fig 5. Forward Characteristic of Reverse Diode

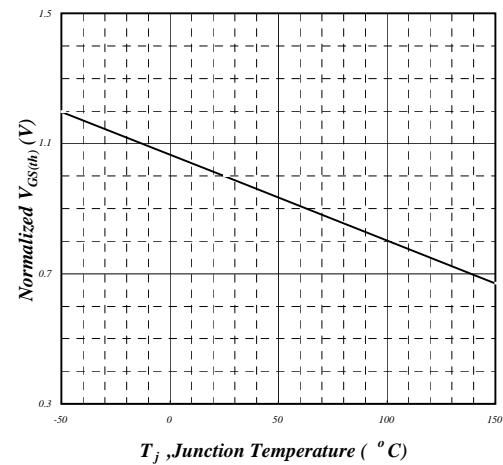
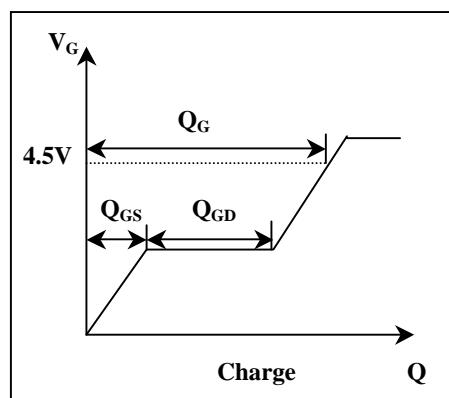
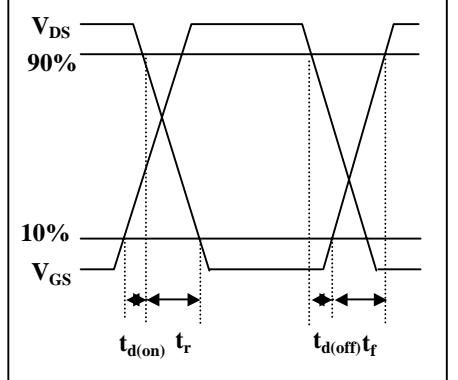
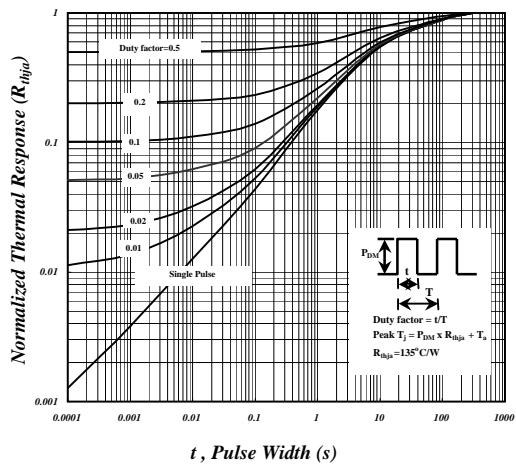
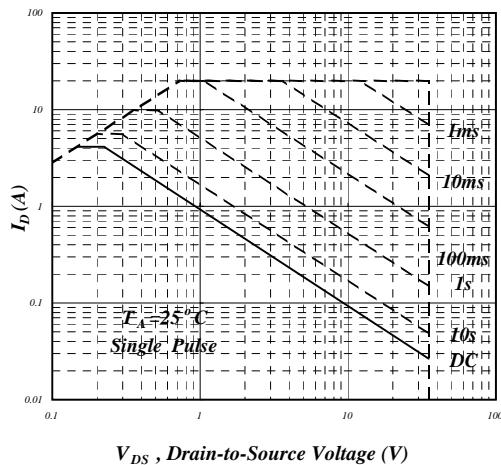
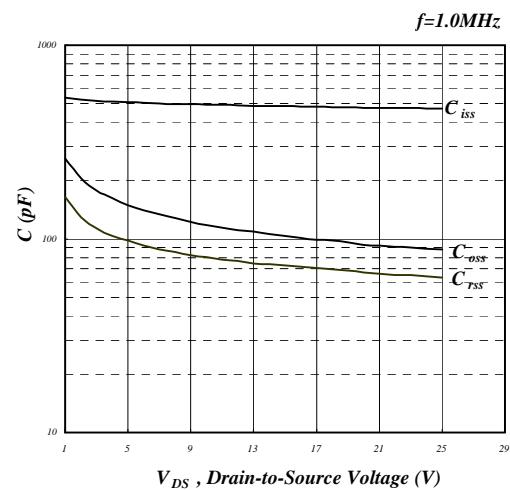
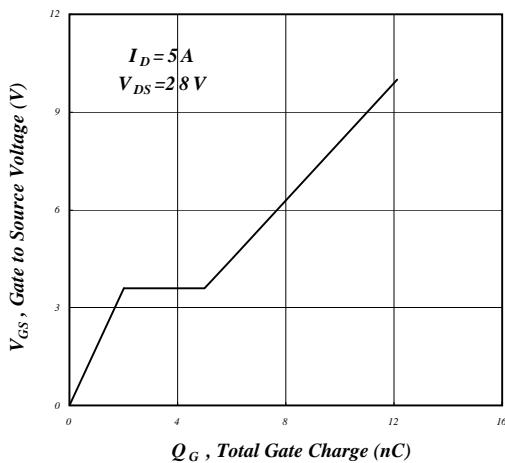


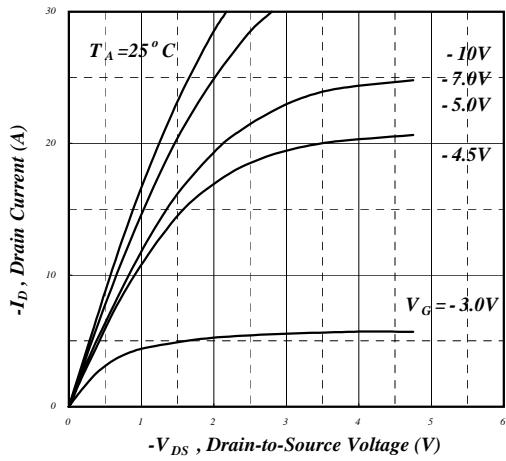
Fig 6. Gate Threshold Voltage v.s. Junction Temperature

**N-Channel****Fig 11. Switching Time Waveform****Fig 12. Gate Charge Waveform**

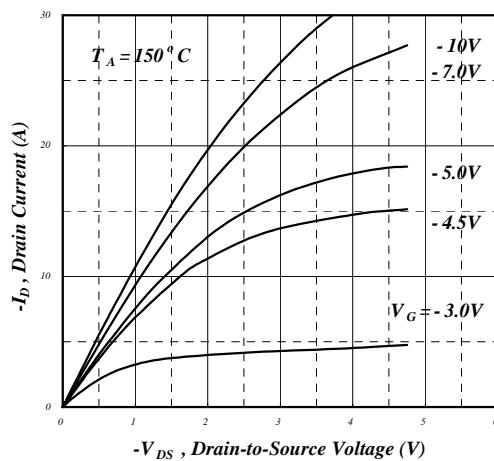


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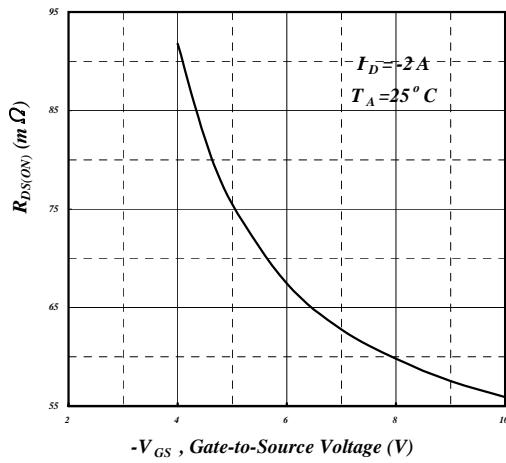
P-Channel



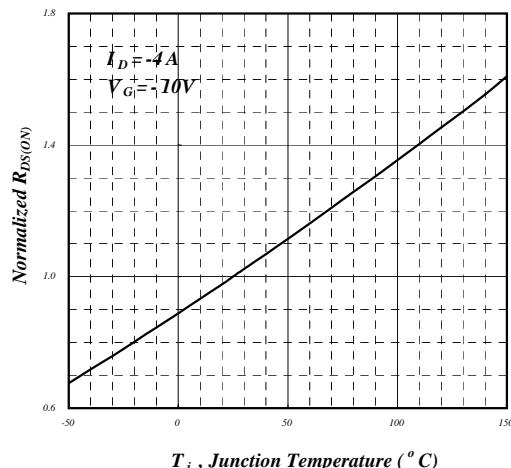
**Fig 1. Typical Output Characteristics**



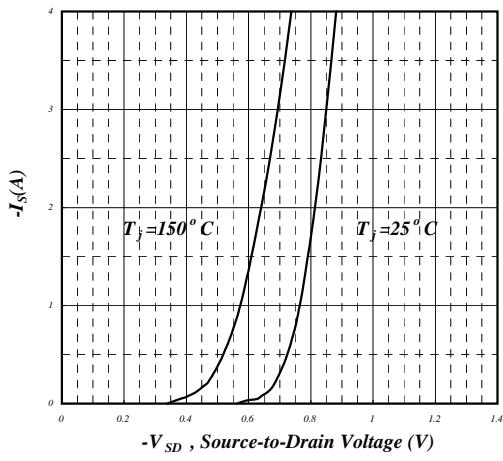
**Fig 2. Typical Output Characteristics**



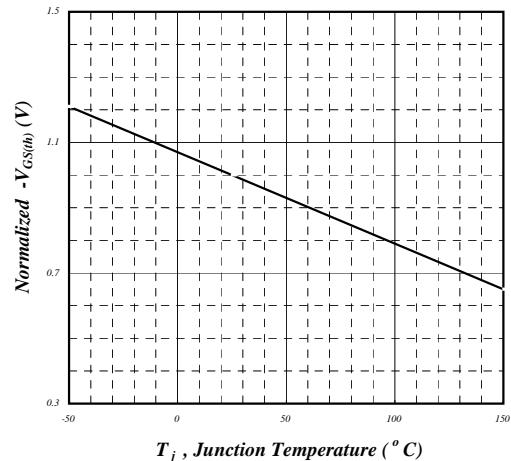
**Fig 3. On-Resistance v.s. Gate Voltage**



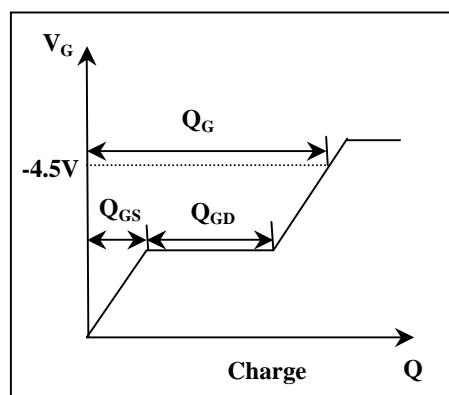
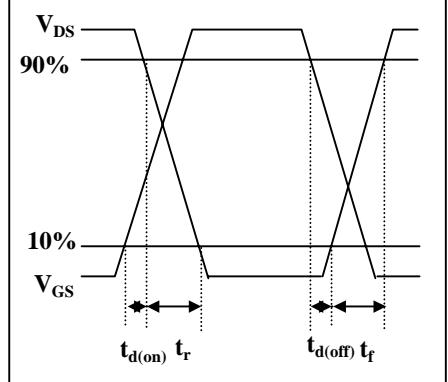
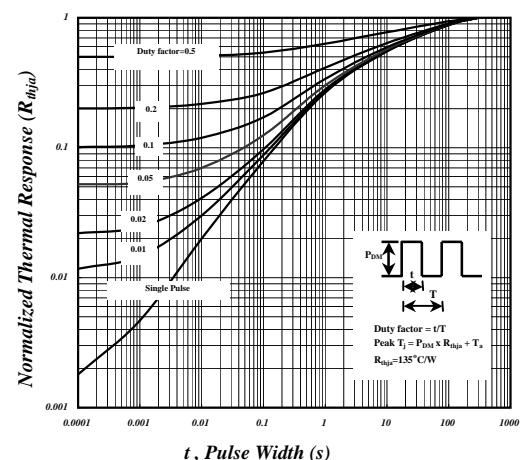
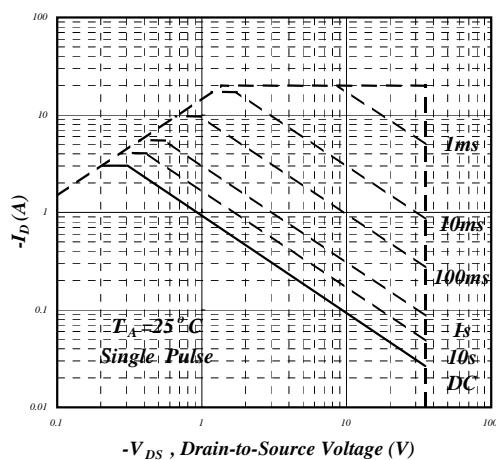
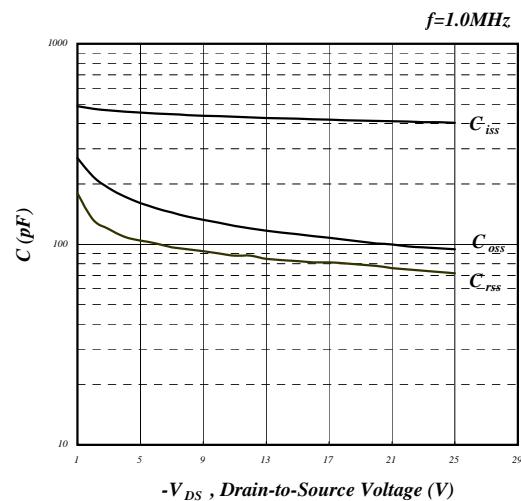
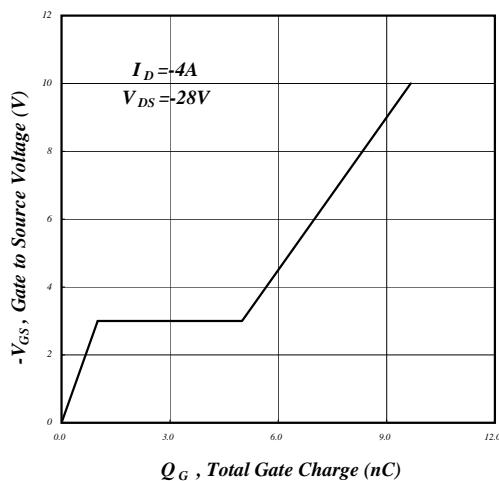
**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



**Fig 5. Forward Characteristic of Reverse Diode**



**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**

**P-Channel****Fig 11. Switching Time Waveform****Fig 12. Gate Charge Waveform**